

Search Notes

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Examiner

Leon J. Harper

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
707	104.1, 10	11/17/2006	LJH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
707	10	11/17/2006	LJH
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR